

Search Notes

Application/Control No.

10/055,526

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
725	118-120, 127- 128,149	2/8/2006	A.S

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR